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Applicant Kunihiro MITSUTAKE et al.							
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U.S. PATENT DOCUMENTS							
Examiner Initial*		Document Number	Date	Name	Class	Sub Class	Filing Date If Appropriate
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Sub Class	Translation Yes or No
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
MCB	IKOTA, M. et al., "Discrimination of Clustered Defects on Wafers Using Statistical Methods", Proc. 1997 Second Int. Workshop Statistical Metrology, pp. 52-55.						
Examiner <i>Mary Catherine Baran</i>	Date Considered 2/7/04						
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